

# DATA SHEET

Model DHS50A05

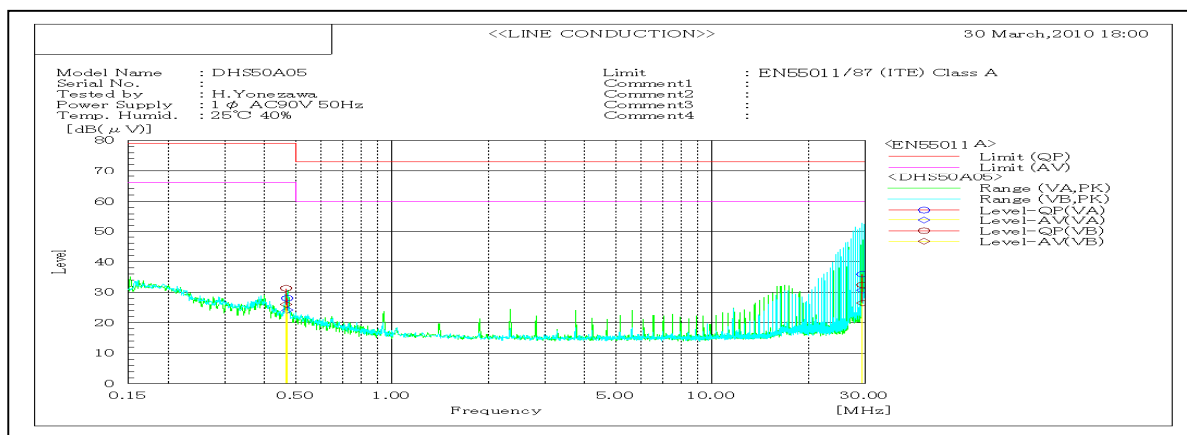
Test EMI  
Line conduction & Radiated emission

Date 26-Apr-10

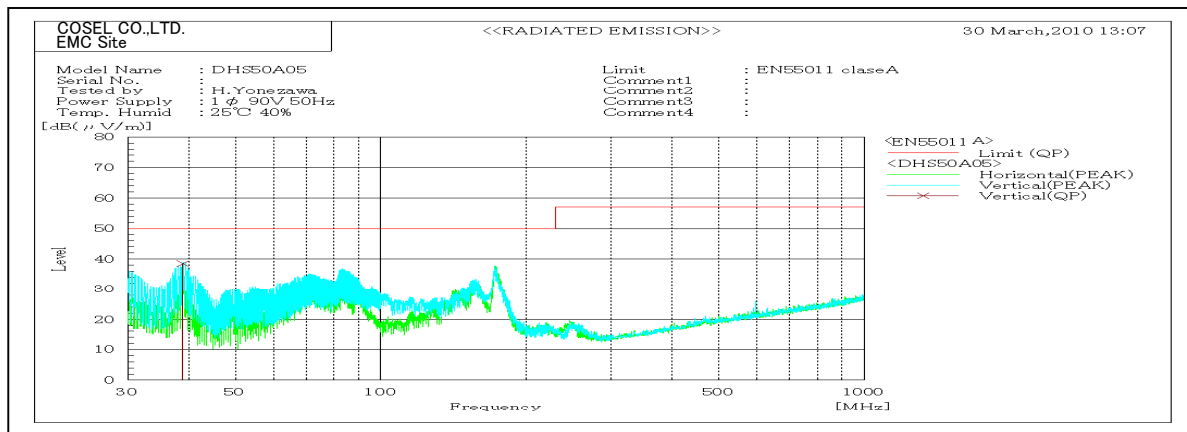
Temp. 25 degreeC

Humid. 40 %RH

Tested by H.Yonezawa



Frequency MHz	Harm	Line Phase	Reading dB( $\mu$ V)		Factor dB	Level dE( $\mu$ V)		Limit dB( $\mu$ V)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46629		VB	21.3	16	10	31.3	26	79	66	47.7	40	Pass	
0.47026		VA	17.9	14	10.1	28	24.1	79	66	51	41.9	Pass	
29.4786		VB	21.4	15.5	11	32.4	26.5	73	60	40.6	33.5	Pass	
29.4904		VA	25.3	20	10.6	35.9	30.6	73	60	37.1	29.4	Pass	



Frequency MHz	Harm	Polariz ation	Level Check	Stabili ty	Reading dB( $\mu$ V)			Space Loss dB	Level dB(mW)			Limit dB(mW)	Limit dB(mW)	Limit dB(mW)	Margin dB			Pass/ Fail	Height cm	Angle deg	Remark
					QP	AV	PK		QP	AV	PK				QP	AV	PK				
38.961		V		Stable	56.5			-18	38.5			50			11.5			Pass	111	282	

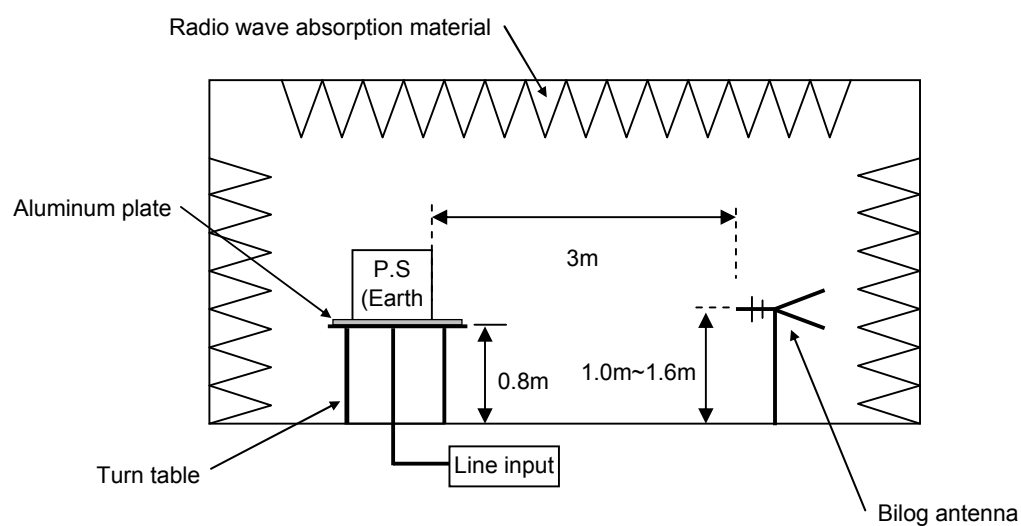
## DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

### 1. Line conduction



### 2. Radiated emission

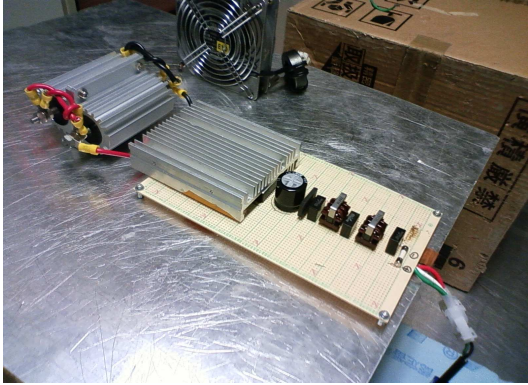


Test: EMI

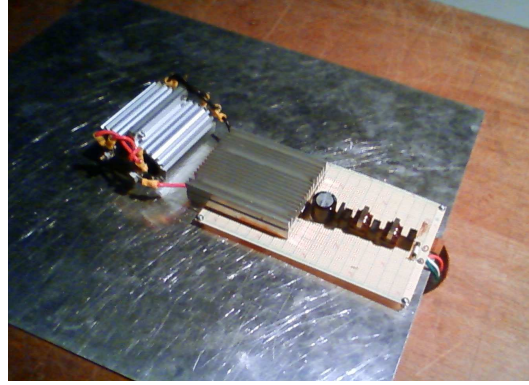
Model Name:DHS50A/DHS100A Series

## ○ Photographs of Test Set-Up

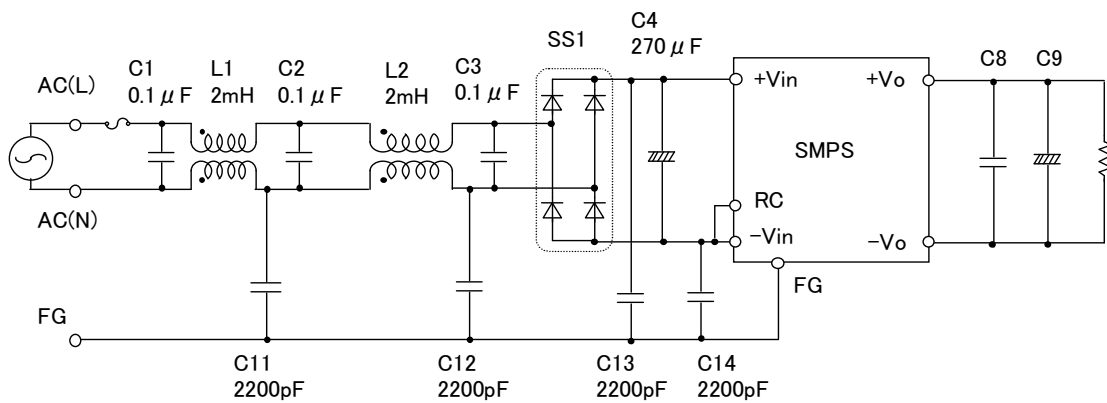
### LINE CONDUCTION



### RADIATED EMISSION



## ○ Test circuit



L1,L2	:	SC-05-200(NEC TOKIN)
SS1	:	D3SBA60(SINDENGEN)
C8	:	DHS50A24/DHS100A24 4.7 μ F
	:	Others 10 μ F
C9	:	DHS50A05/DHS100A05 2200 μ F
	:	DHS50A12/DHS100A12 470 μ F
	:	DHS50A15/DHS100A15 470 μ F
	:	DHS50A24/DHS100A24 220 μ F